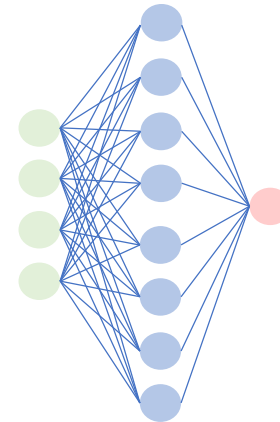
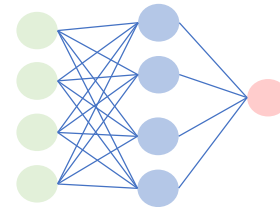
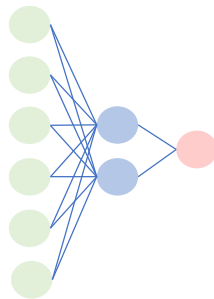
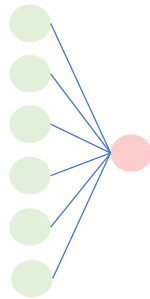


Learning (with) deep random networks

Hugo Cui

SPOC lab, EPFL, Switzerland

Cargèse 2023



Learning curves of generic features maps for realistic datasets with a teacher-student model, Loureiro, Gerbelot, **HC**, Goldt, Mézard, Krzakala, Zdeborová, NeurIPS 2021

Bayes-optimal learning of deep random networks of extensive width, **HC**, Krzakala, Zdeborová, ICML 2023

Deterministic equivalent and gaussian universality of deep random features learning, Schröder, **HC**, Dmitriev, Loureiro, ICML 2023



Bruno Loureiro
ENS



Cédric Gerbelot
NYU



Sebastian Goldt
SISSA



Dominik Schröder
ETH



Florent Krzakala
EPFL



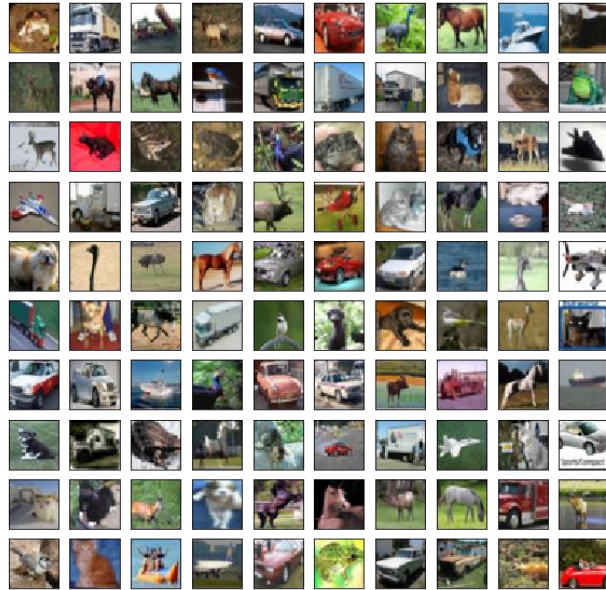
Lenka Zdeborová
EPFL



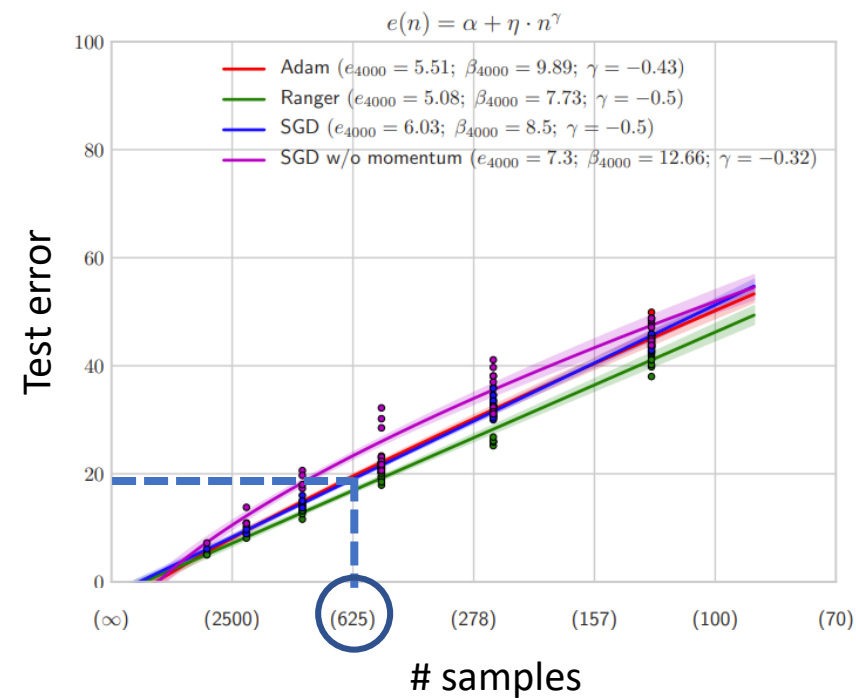
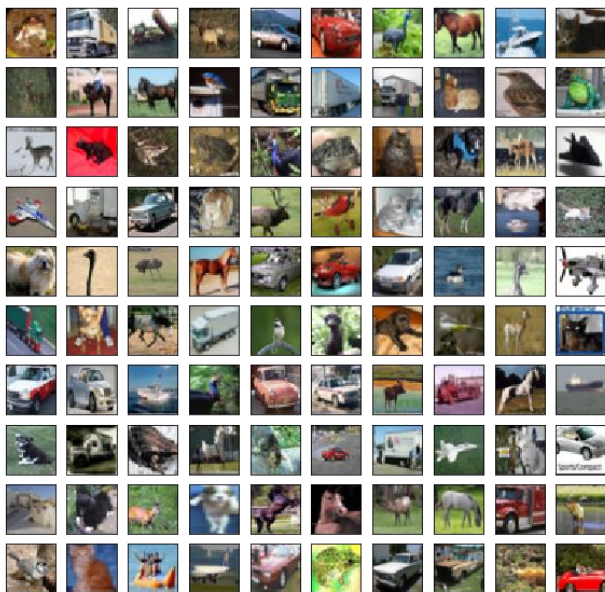
Marc Mézard
Bocconi



Daniil Dmitriev
ETH



Question: *What is the best accuracy* one can achieve from 600 training samples?



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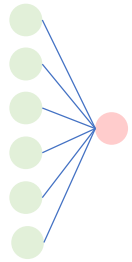
(Empirical) Answer: Probably $\approx 82\%$, using good networks.

For a train set $\mathcal{D} = \{x^\mu, y^*(x^\mu)\}_{\mu=1}^n$ of given size n , what is *the lowest achievable test error* ϵ_g one can hope to achieve?

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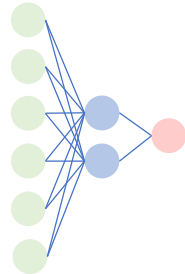
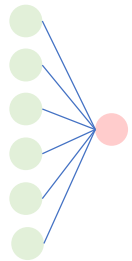
When the target function is *parametric*, the lowest (**Bayes-optimal**) test error is given by Bayesian inference.

Theoretical testbeds: random neural networks



Barbier et al, *Optimal errors and phase transitions in high-dimensional generalized linear models*, PNAS 2017

Theoretical testbeds: random neural networks

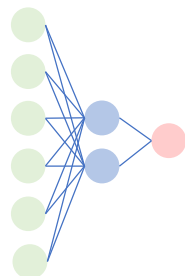
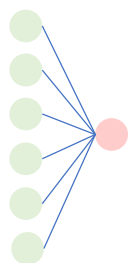


width \ll *dimension*

Barbier et al, *Optimal errors and phase transitions in high-dimensional generalized linear models*, PNAS 2017

Aubin et al, *The committee machine: Computational to statistical gaps*, NeurIPS 2019

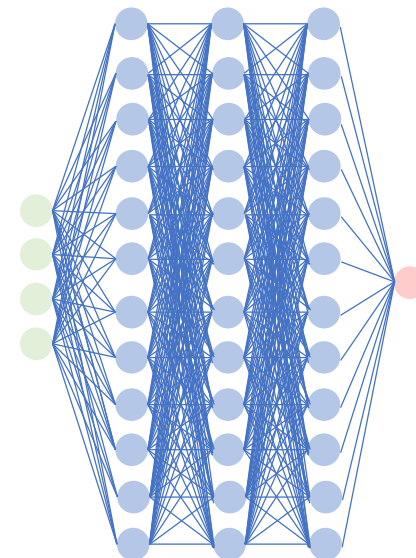
Theoretical testbeds: random neural networks



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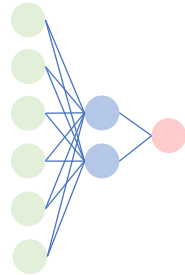
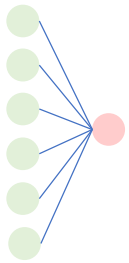
Aubin et al, *The committee machine: Computational to statistical gaps*, NeurIPS 2019



width \gg *dimension*

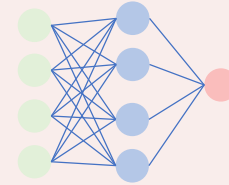
Neal, *Priors for infinite nets*, Uni. Toronto 1996
Williams, *Computing with infinite networks*, NeurIPS 1996
Lee et. al., *Deep Neural Networks as GPs*, ICLR 2018

Theoretical testbeds: random neural networks



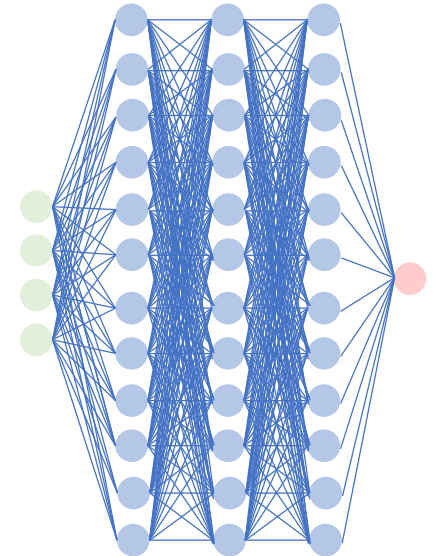
width \ll *dimension*

Barbier et al, *Optimal errors and phase transitions in high-dimensional generalized linear models*, PNAS 2017



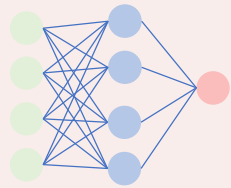
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Aubin et al, *The committee machine: Computational to statistical gaps*, NeurIPS 2019



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Neal, *Priors for infinite nets*, Uni. Toronto 1996
Williams, *Computing with infinite networks*, NeurIPS 1996
Lee et. al., *Deep Neural Networks as GPs*, ICLR 2018



width \sim *dimension*

Some related works:

High-dimensional formulae for sign/ReLU Bayes regression

Li and Sompolinsky, *Statistical mechanics of deep linear neural networks: The backpropagating kernel renormalization*, PRX, 2021.

Ariosto et al., *Statistical mechanics of deep learning beyond the infinite-width limit*. ArXiv, abs/2209.04882, 2022.

(Non)-asymptotics for linear networks

Zavatone-Veth, Tong and Pehlevan, *Contrasting random and learned features in deep bayesian linear regression*, PRE 2022

Hanin and Zlokapa, *Bayesian interpolation with deep linear networks*. ArXiv, abs/2212.14457, 2022

Recent advances in neighbouring regimes

Camilli, Tieplov, Barbier, *Fundamental limits of overparametrized shallow networks for supervised learning*, ArXiv, abs/2307.05635

(Data)

Gaussian data: $x \sim \mathcal{N}(0, \Sigma)$

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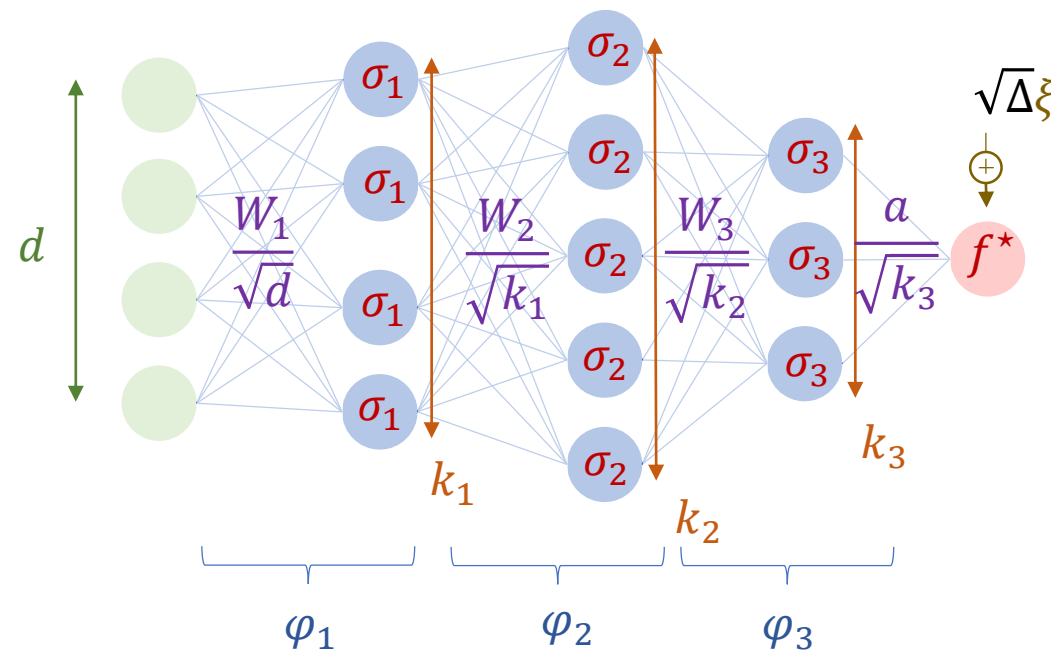
(Target)

$$y^*(x) = f^* \left(\frac{a^\top}{\sqrt{k_L}} \varphi_L \circ \dots \circ \varphi_1(x) + \sqrt{\Delta} \xi \right)$$

$$\text{with layers } \varphi_\ell(h) = \sigma_\ell \left(\frac{W_\ell}{\sqrt{k_{\ell-1}}} h \right)$$

Odd activations σ_ℓ

$$(W_\ell)_{ij} \sim \mathcal{N}(0, \Delta_\ell), \quad a_i \sim \mathcal{N}(0, \Delta_a), \quad \xi \sim \mathcal{N}(0, 1)$$



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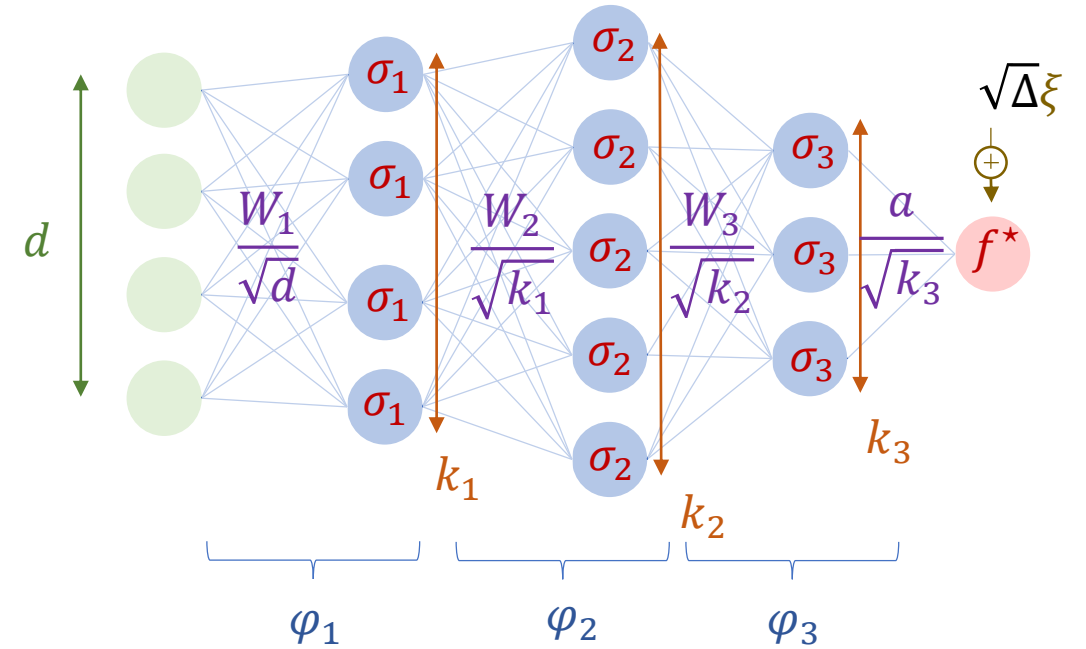
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(Train set)

Supervised learning with n i.i.d samples $\mathcal{D} = \{x^\mu, y^*(x^\mu)\}_{\mu=1}^n$



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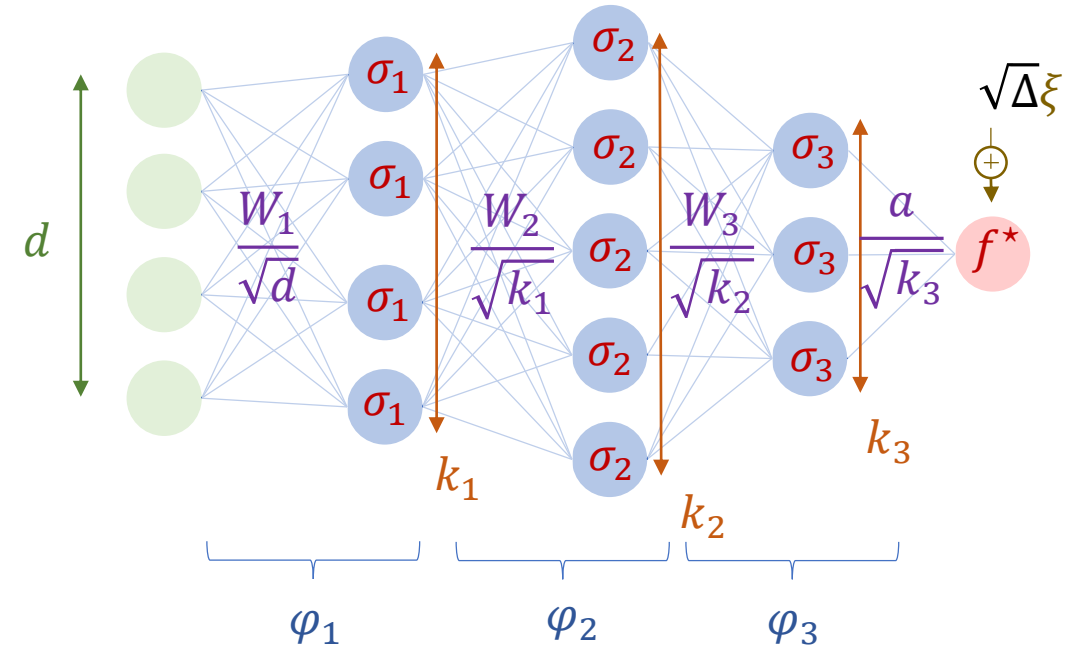
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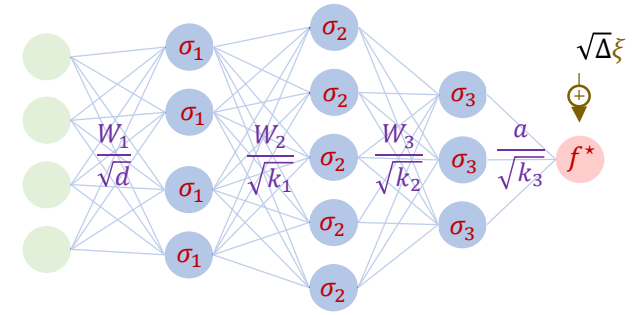
Proportional extensive-width limit

$$n, d, k_1, \dots, k_L \rightarrow \infty$$

with

$$\alpha = \frac{n}{d}, \gamma_\ell = \frac{k_\ell}{d} = \mathcal{O}(1)$$

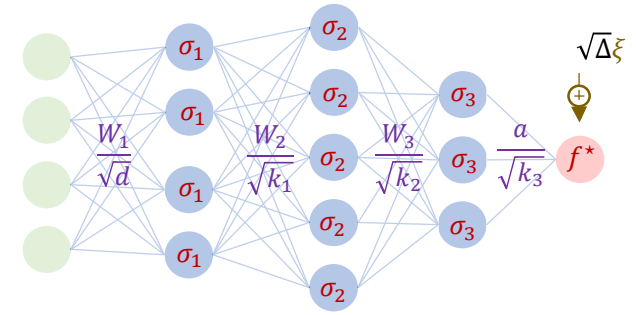
Suppose the architecture, priors, activations are known.
The best test error is then given by *Bayesian inference*:



Bayes posterior

$$\mathbb{P}(a, \{W_\ell\}_{\ell=1}^L | \mathcal{D}) \propto e^{-\frac{\|a\|^2}{2\Delta_a} - \sum_{\ell=1}^L \frac{\|W_\ell\|_F^2}{2\Delta_\ell}} \times \prod_{\ell=1}^L \int \frac{d\xi e^{-\frac{\xi^2}{2}}}{\sqrt{2\pi}} \delta \left(y^*(x^\mu) - f^* \left(\frac{a^\top}{\sqrt{k_L}} \varphi_L \circ \dots \circ \varphi_1(x) + \sqrt{\Delta} \xi \right) \right)$$

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Regression ($f^* = id$)

$$\epsilon_{g,\text{reg}}^{\text{BO}} = \mathbb{E}_{\mathcal{D}, \{W_\ell^*\}_{\ell=1}^L, \mathbf{a}_*} \mathbb{E}_{\mathbf{x}, y} \left[\left(y - \langle \hat{y}(\mathbf{x}) \rangle_{\mathbf{a}, \{W_\ell\}_{\ell=1}^L \sim \mathbb{P}} \right)^2 \right]$$

Classification ($f^* = \text{sign}$)

$$\epsilon_{g,\text{class}}^{\text{BO}} = \mathbb{E}_{\mathcal{D}, \{W_\ell^*\}_{\ell=1}^L, \mathbf{a}_*} \mathbb{P}_{\mathbf{x}, y} \left[y \neq \text{sign} \left(\langle \text{sign}(\hat{y}(\mathbf{x})) \rangle_{\mathbf{a}, \{W_\ell\}_{\ell=1}^L \sim \mathbb{P}} \right) \right].$$

Q1. Can one provide a sharp asymptotic characterization of the Bayes-optimal error?

Q2. How do the test errors achieved by ERM algorithms in practice compare?

Outline

Preliminaries: Second-order statistics of random(-ish) neural nets

A1 Bayes-optimal test errors

A2 ERM test errors

Preliminaries: Second-order statistics of random(-ish) neural nets

Why second order statistics?

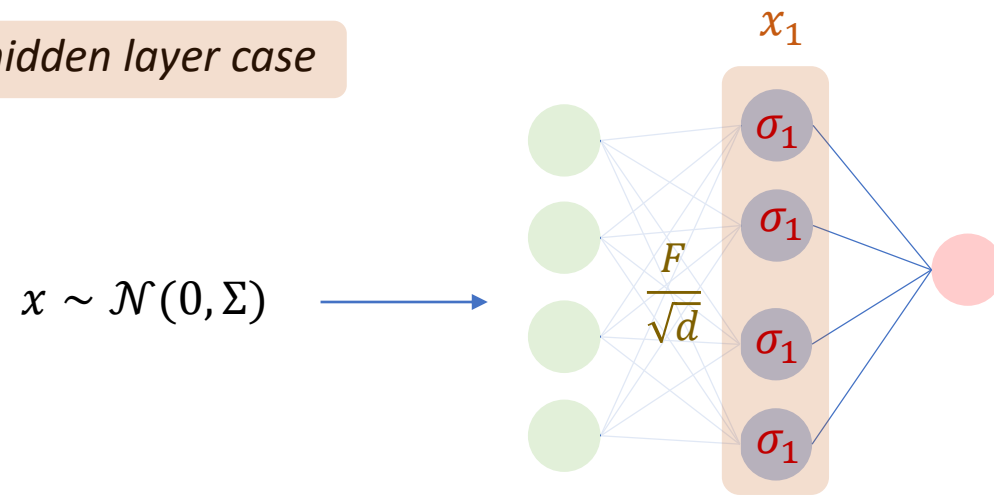
1. Appear naturally in the replica computation.
2. **Gaussian universality** : in a number of simple ERM settings, the test error only depends on the second order statistics of the data (*more later*)

Song Mei and Andrea Montanari. *Generalization Error of Random Features Regression: Precise Asymptotics and the Double Descent Curve*. *Commun. Pure Appl. Math.*, 2022

Hong Hu and Yue M. Lu. *Universality Laws for High-Dimensional Learning with Random Features*. *IEE Trans. Inf. Theory*

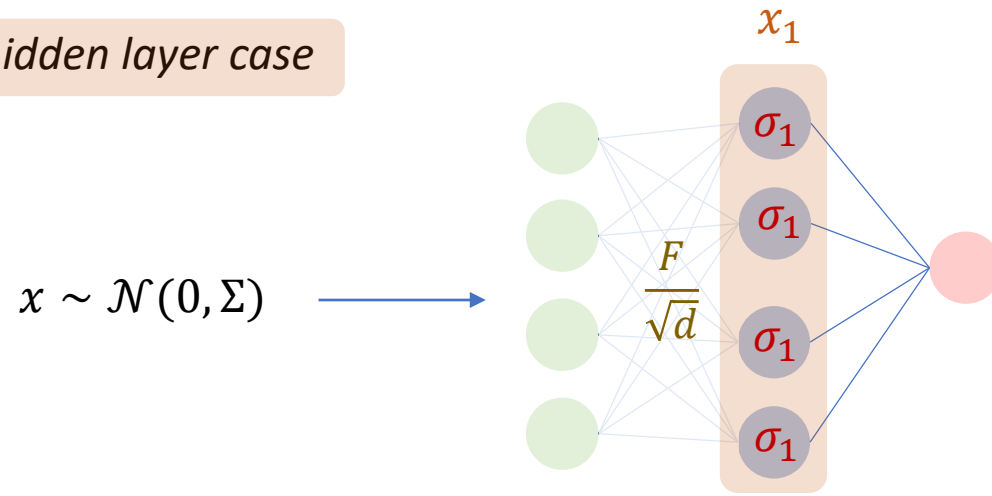
Federica Gerace, Bruno Loureiro, Florent Krzakala, Marc Mezard, and Lenka Zdeborova. *Generalisation error in learning with random features and the hidden manifold model*. *ICML 2020*

The shallow $L=1$ hidden layer case



For fixed F , what is the covariance $\Omega = \langle x_1 x_1^\top \rangle_x$ of the last layer post-activation wrt the Gaussian input randomness?

The shallow $L=1$ hidden layer case



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(Gaussian Equivalence Property)

Defining

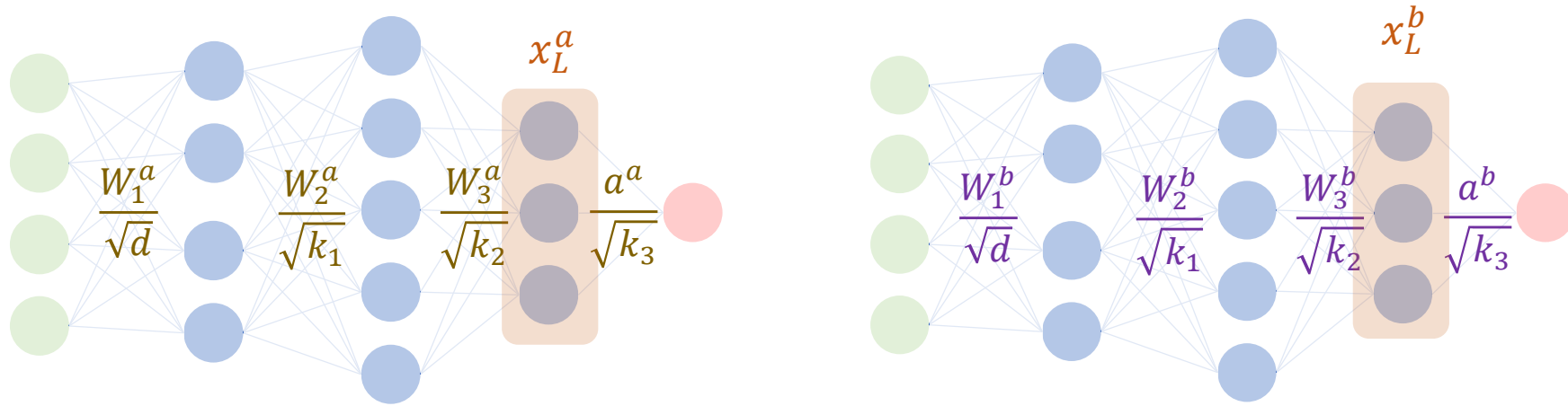
$$\kappa_1 = \mathbb{E}_{z \sim \mathcal{N}(0,1)} [\sigma_1(z)z]$$

$$\kappa_* = \sqrt{\mathbb{E}_{z \sim \mathcal{N}(0,1)} [\sigma_1(z)^2] - \kappa_1^2}$$

then simply

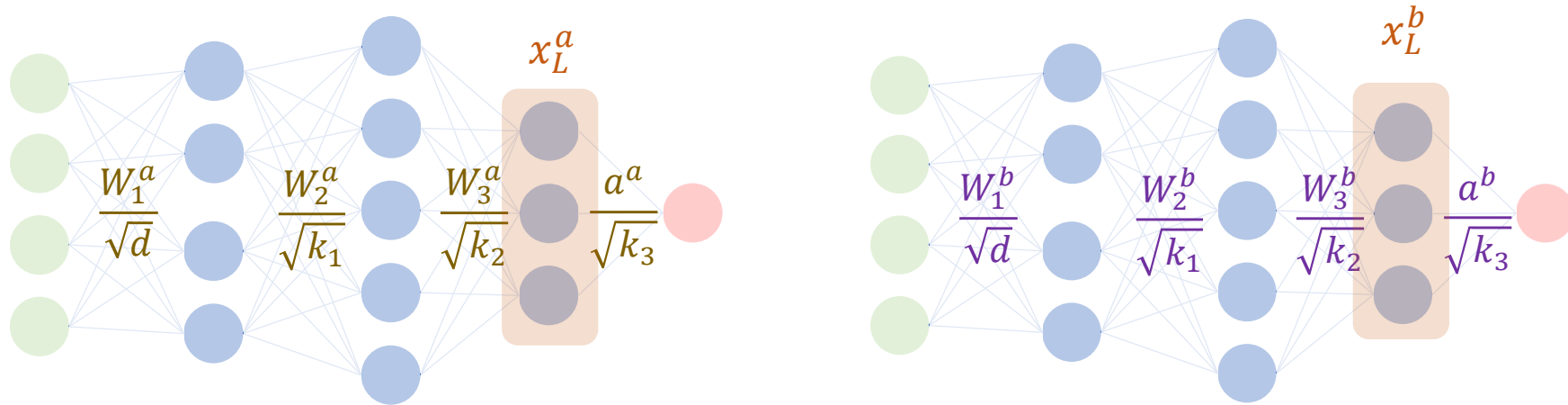
$$\Omega = \kappa_1^2 \frac{F \Sigma F^\top}{d} + \kappa_*^2 \mathbb{I}_k$$

Draw two networks W_1^a, \dots, W_L^a, a^a and W_1^b, \dots, W_L^b, a^b i.i.d from the Bayes posterior.



What is the covariance $\Omega_L^{ab} = \langle x_L^a x_L^{b\top} \rangle_x$?

Draw two networks W_1^a, \dots, W_L^a, a^a and W_1^b, \dots, W_L^b, a^b i.i.d from the Bayes posterior.



What is the covariance $\Omega_L^{ab} = \langle x_L^a x_L^{b\top} \rangle_x$?

(Deep Bayes conjecture)

Defining

$$r_{\ell+1} = \Delta_{\ell+1} \mathbb{E}_{z \sim \mathcal{N}(0, r_\ell)} [\sigma_\ell(z)^2],$$

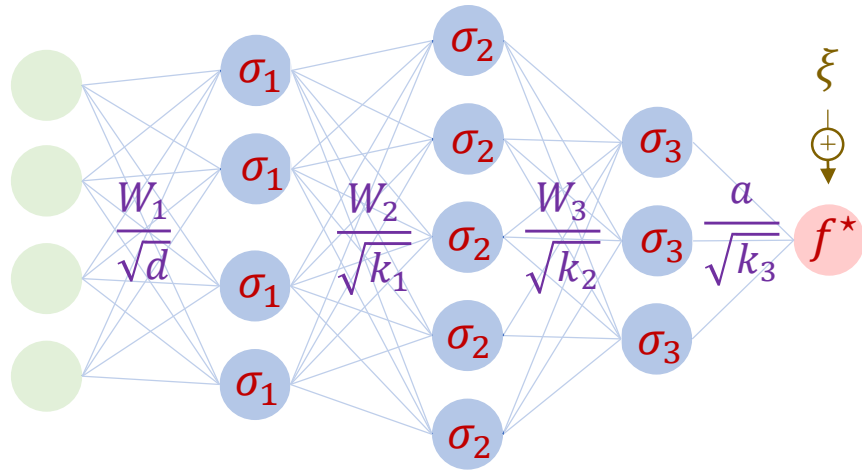
$$\kappa_1^{(\ell)} = \frac{1}{r_\ell} \mathbb{E}_{z \sim \mathcal{N}(0, r_\ell)} [z \sigma_\ell(z)],$$

$$\kappa_*^{(\ell)} = \sqrt{\mathbb{E}_{z \sim \mathcal{N}(0, r_\ell)} [\sigma_\ell(z)^2] - r_\ell \left(\kappa_1^{(\ell)} \right)^2},$$

Ω_L^{ab} is given by the L th term of the recursion

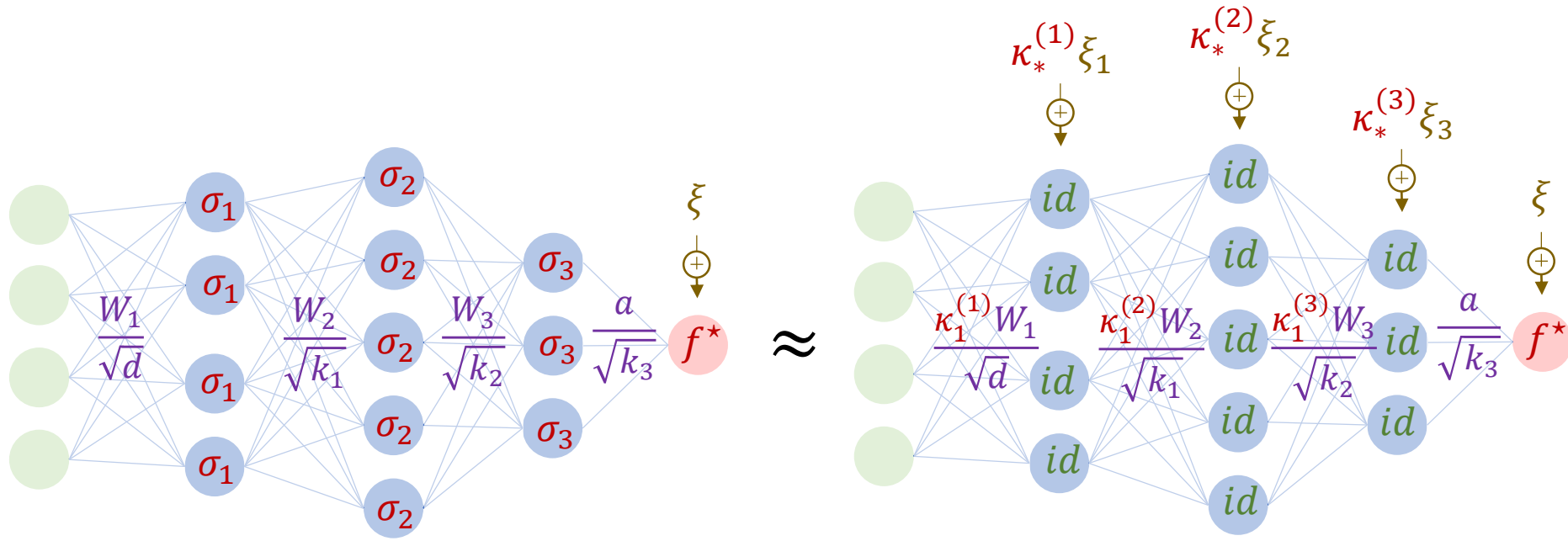
$$\Omega_\ell^{ab} = \left(\kappa_1^{(\ell)} \right)^2 \frac{W_\ell^a \Omega_{\ell-1}^{ab} W_\ell^{b\top}}{k_{\ell-1}} + \delta_{ab} \left(\kappa_*^{(\ell)} \right)^2 \mathbb{I}_{k_\ell}$$

In terms of second-order activation statistics,



Non-linear deep network

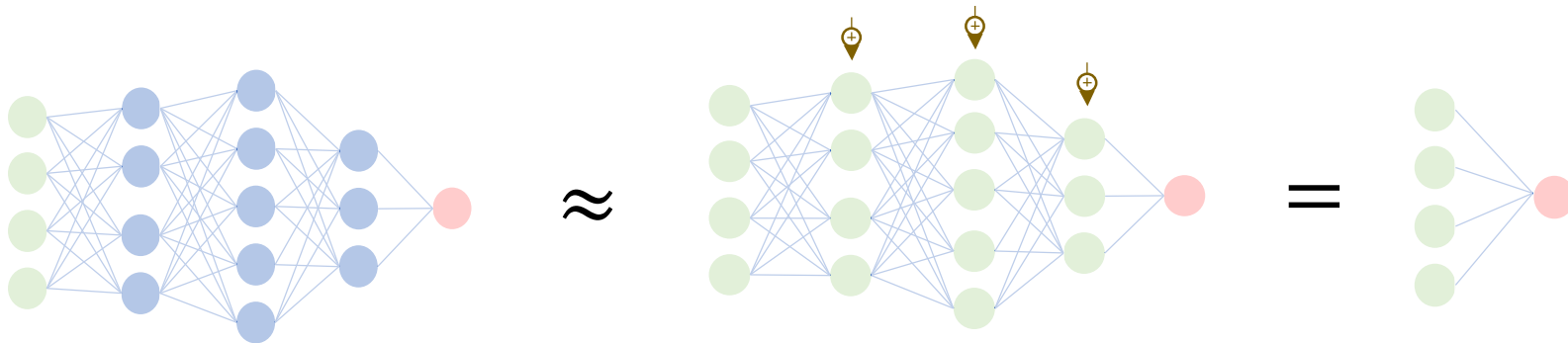
In terms of second-order activation statistics,



Non-linear deep network

Noisy, linear deep network

Q1. Can one conjecture a sharp asymptotic characterization of the Bayes-optimal error?



$$y^*(x) = f^* \left(\frac{a^\top}{\sqrt{k_L}} \varphi_L \circ \dots \circ \varphi_1(x) + \sqrt{\Delta} \mathcal{N}(0,1) \right)$$

With layers $\varphi_\ell(h) = \sigma_\ell \left(\frac{W_\ell}{\sqrt{k_{\ell-1}}} h \right)$

$$(W_\ell)_{ij} \sim \mathcal{N}(0, \Delta_\ell), \quad a_i \sim \mathcal{N}(0, \Delta_a)$$

$$y^{\text{eq}}(x) = f^* \left(\rho \frac{\theta^\top x}{\sqrt{d}} + \epsilon_r \mathcal{N}(0,1) \right)$$

$$\epsilon_r \equiv \sum_{\ell_0=1}^{L-1} (\kappa_*^{(\ell_0)})^2 \Delta_a \prod_{\ell=\ell_0+1}^L (\kappa_1^{(\ell)})^2 \Delta_\ell + (\kappa_*^{(L)})^2 \Delta_a + \Delta$$

With

$$\rho \equiv \Delta_a \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 \Delta_\ell$$

$$\theta_i \sim \mathcal{N}(0,1)$$

Conjecture : these two networks are characterized by the *same Bayes optimal errors*

Regression

$$\epsilon_{g,\text{reg}}^{\text{BO}} = \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 \left(\Delta_a \left(\int z d\mu(z) \right) \prod_{\ell=1}^L \Delta_\ell - q \right) + \epsilon_r$$

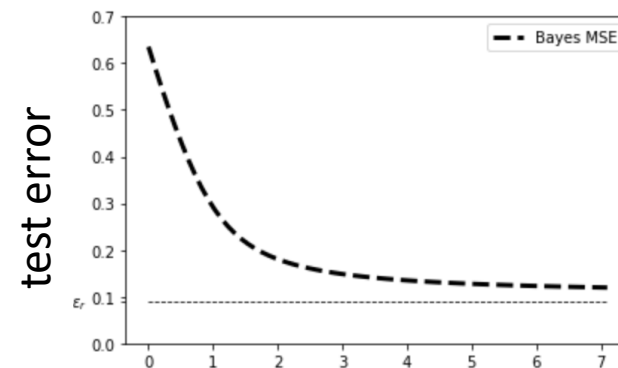
$$q = \frac{1}{2} \int \frac{\alpha \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 z^2 \Delta_a^2 \prod_{\ell=1}^L \Delta_\ell^2}{\epsilon_{g,\text{reg}}^{\text{BO}} + \alpha \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 z \Delta_a \prod_{\ell=1}^L \Delta_\ell} d\mu(z).$$

Classification

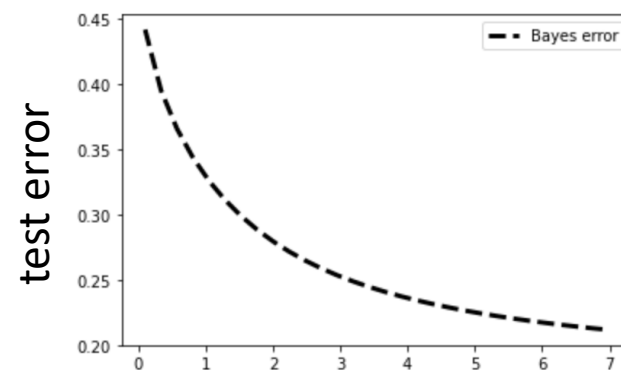
$$\epsilon_{g,\text{class}}^{\text{BO}} = \frac{1}{\pi} \arccos \left[\frac{\sqrt{\prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 q}}{\sqrt{\Delta_a \int z d\mu(z) \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 \Delta_\ell + \epsilon_r}} \right]$$

$$\left\{ \begin{array}{l} q = \int \frac{\hat{q} \Delta_a^2 \prod_{\ell=1}^L \Delta_\ell^2 z^2}{\hat{q} z \Delta_a \prod_{\ell=1}^L \Delta_\ell + 1} d\mu(z) \\ \hat{q} = \frac{2\alpha \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2}{\Delta_a \int z d\mu(z) \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 \Delta_\ell + \epsilon_r - \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 q} \\ \quad - \frac{\Delta_a \int z d\mu(z) \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 \Delta_\ell + \epsilon_r + \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 q}{\Delta_a \int z d\mu(z) \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 \Delta_\ell + \epsilon_r - \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 q} \xi^2 \\ \int \frac{d\xi}{(2\pi)^{\frac{3}{2}}} \frac{2e}{1 - \text{erf} \left(\frac{\prod_{\ell=1}^L \kappa_1^{(\ell)} \sqrt{q} \xi}{\sqrt{2 \left(\Delta_a \int z d\mu(z) \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 \Delta_\ell + \epsilon_r - \prod_{\ell=1}^L (\kappa_1^{(\ell)})^2 q \right)}} \right)} \end{array} \right.$$

depth = 3, $\sigma = \tanh$

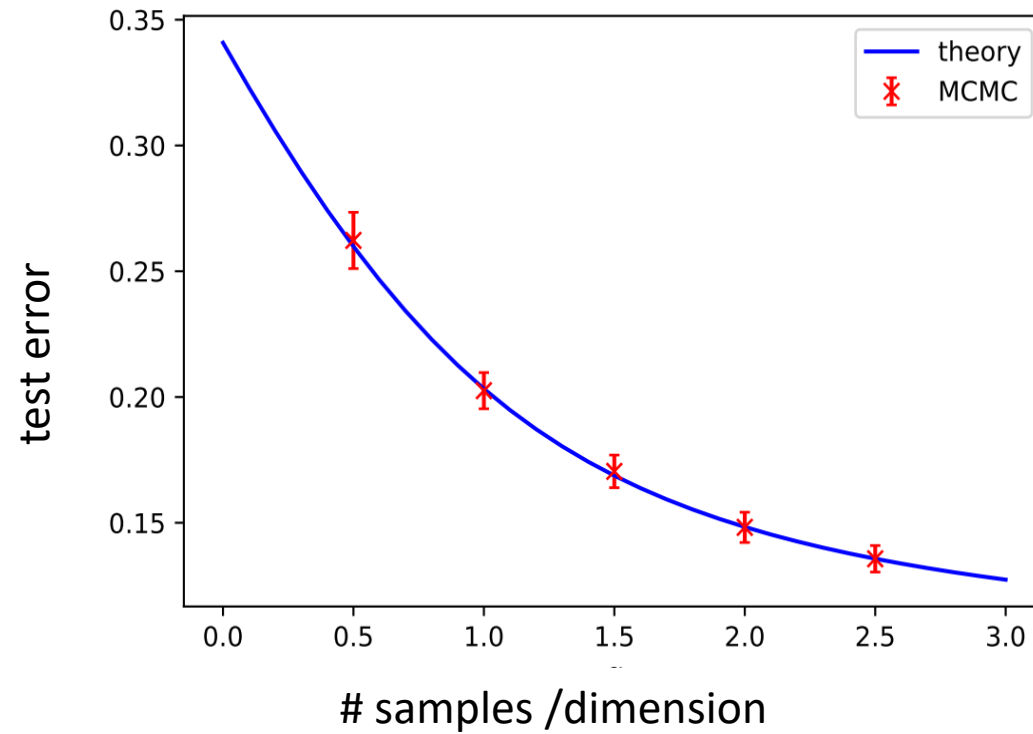


samples / dimension



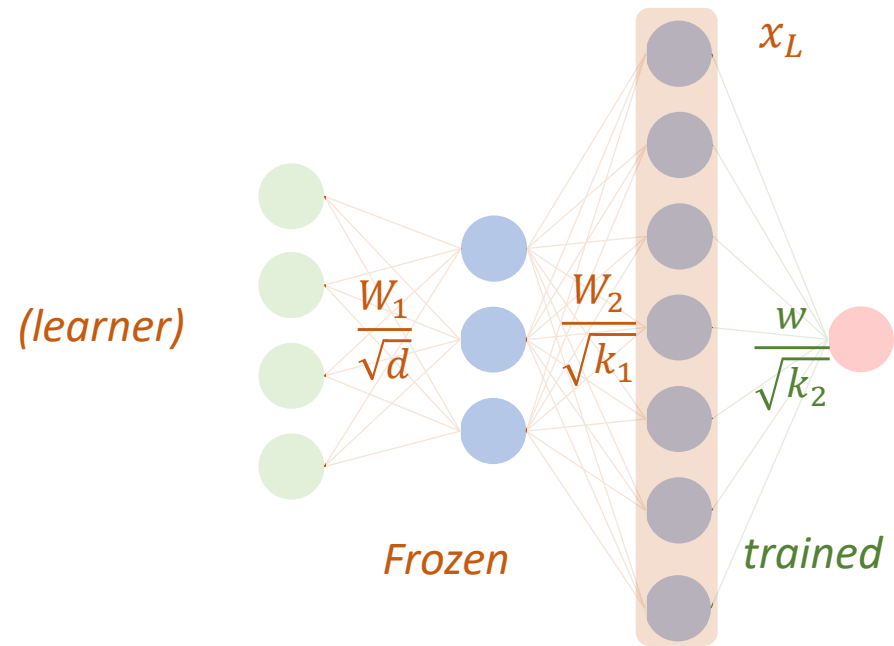
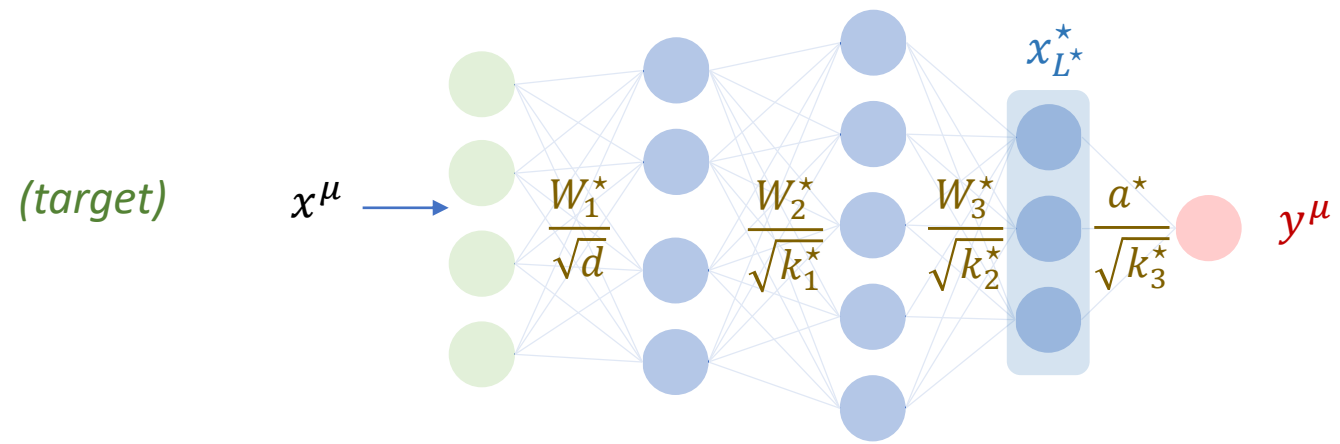
samples / dimension

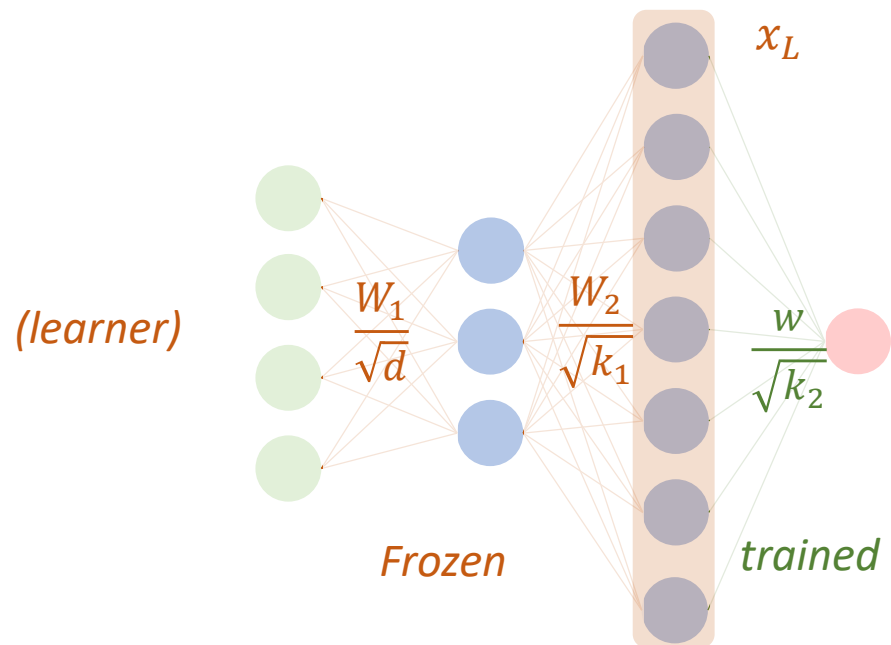
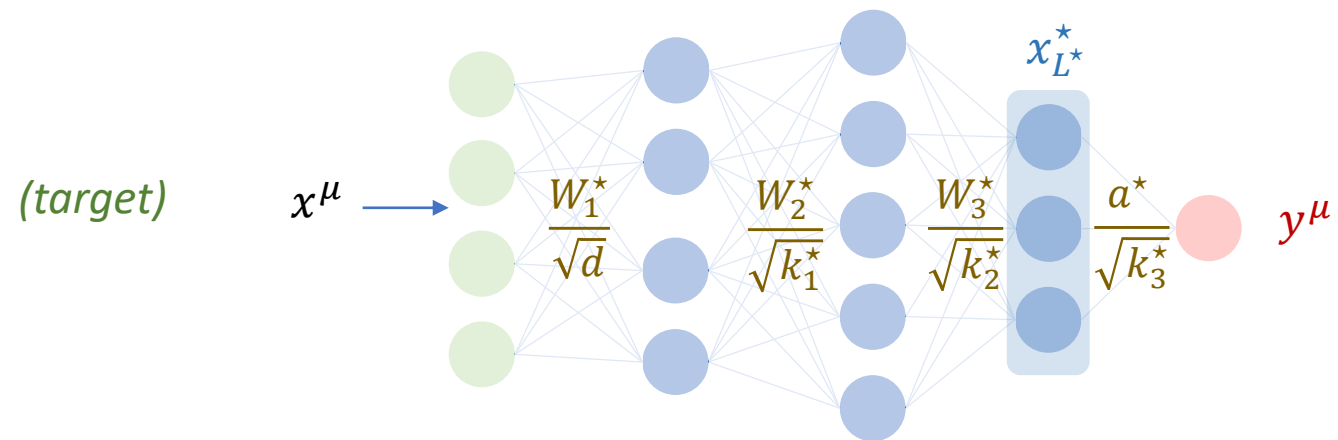
$$\text{depth} = 2, \sigma = \text{ReLU} - 1/\sqrt{2\pi}$$



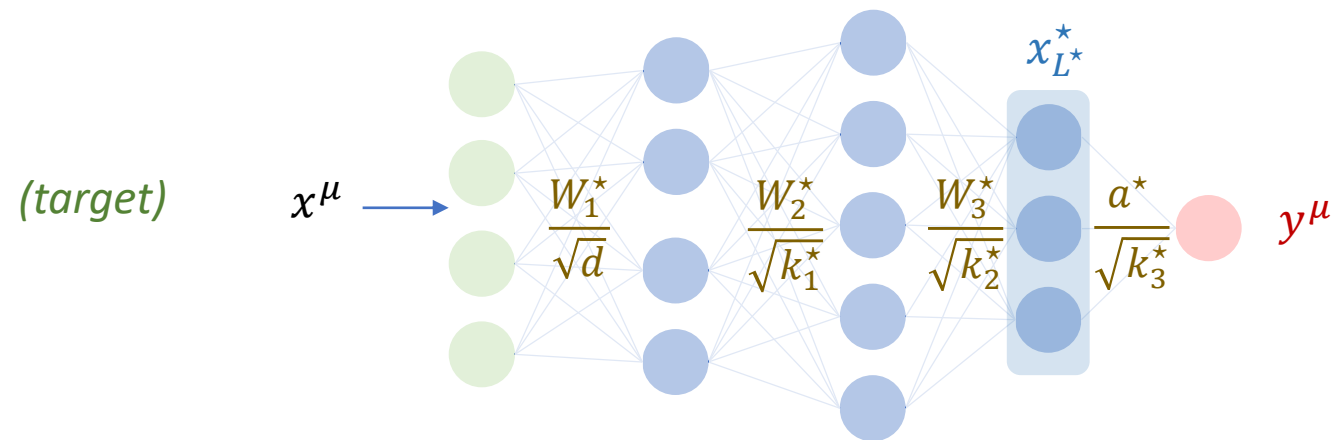
✓ **Q1.** Can one provide a sharp asymptotic characterization of the Bayes-optimal error?

Q2. How do the test errors achieved by ERM algorithms in practice compare?

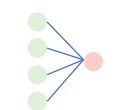
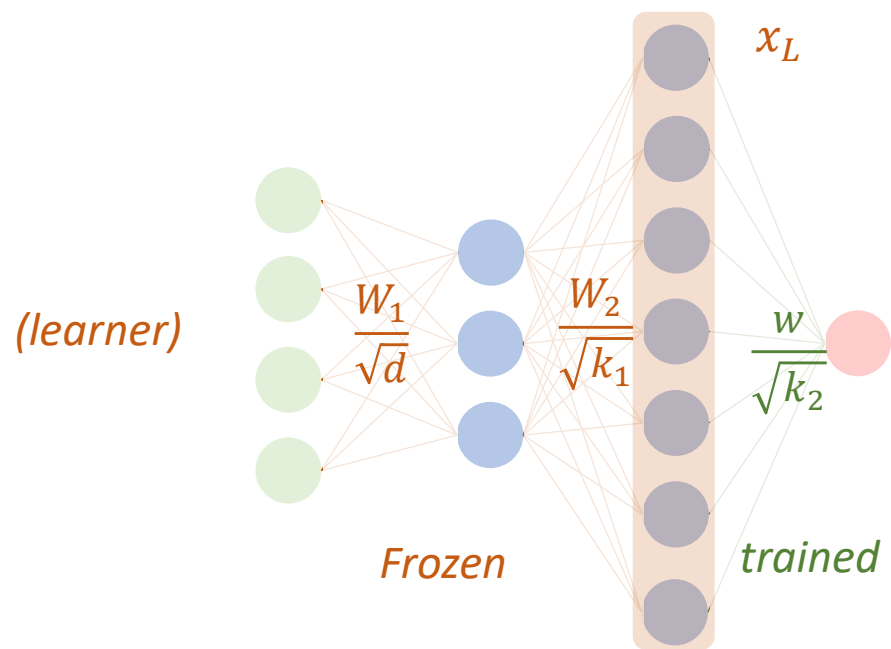




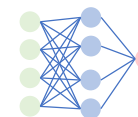
$$\hat{w} = \underset{w}{\operatorname{argmin}} \left(\sum_{\mu=1}^n g \left(y^\mu, \frac{w^\top x_L^\mu}{\sqrt{k_L}} \right) + r(w) \right)$$



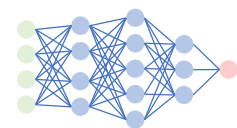
$$\hat{w} = \underset{w}{\operatorname{argmin}} \left(\sum_{\mu=1}^n g \left(y^\mu, \frac{w^\top x_L^\mu}{\sqrt{k_L}} \right) + r(w) \right)$$



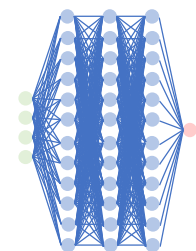
- Ridge, LASSO, elastic net...
- Logistic / hinge / ridge classification



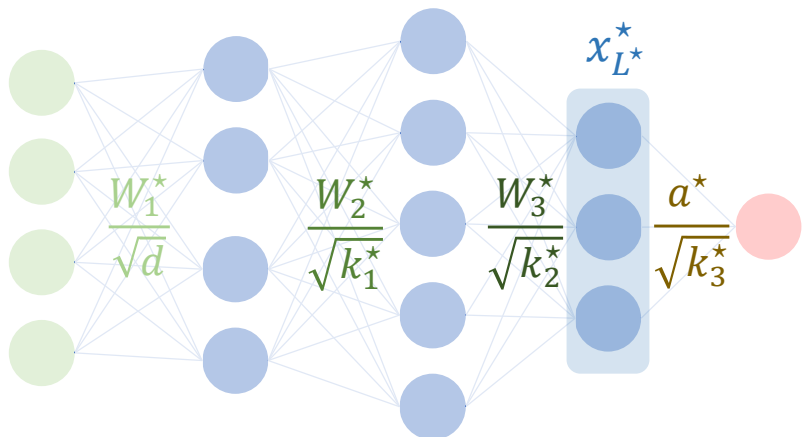
- Random Features



- Deep Random Features

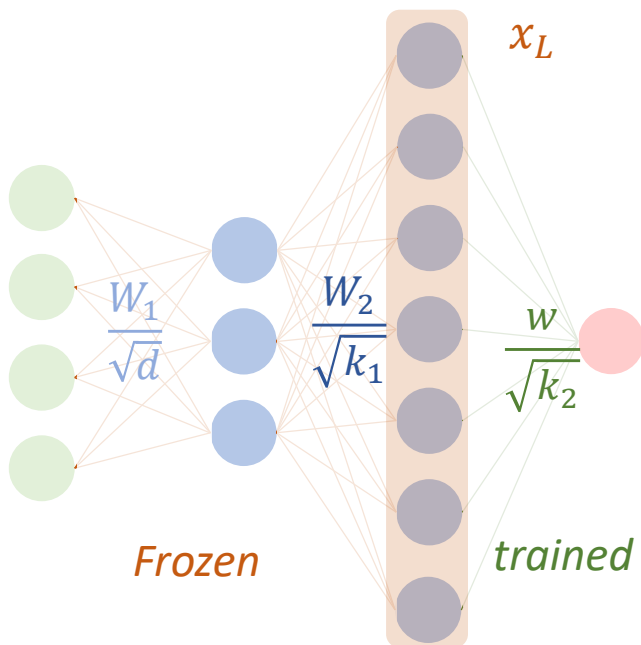


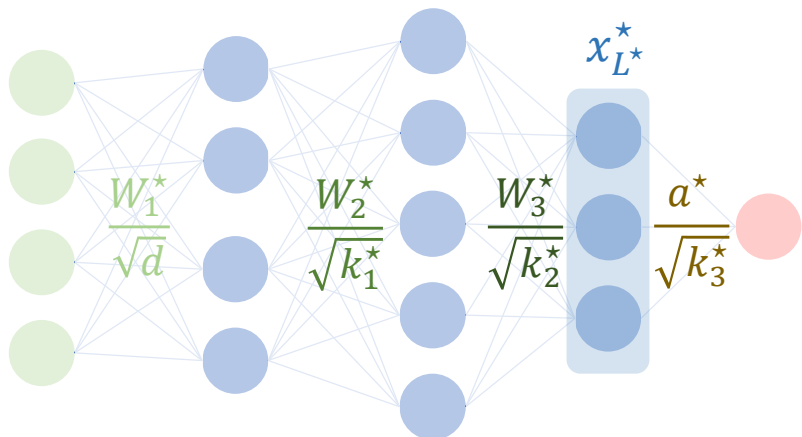
- Kernel regression/classification



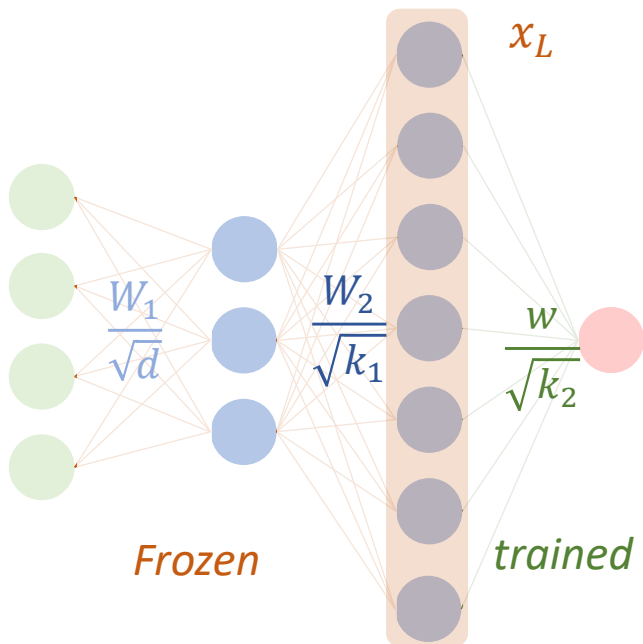
Introduce the **Gaussian clones** u, v of x_L, x_L^*

$$u, v \sim \mathcal{N} \left(0, \begin{bmatrix} \langle x_L x_L^\top \rangle & \langle x_L x_{L^*}^{*\top} \rangle \\ \langle x_{L^*}^* x_L^\top \rangle & \langle x_{L^*}^* x_{L^*}^{*\top} \rangle \end{bmatrix} \right)$$





(ERM)



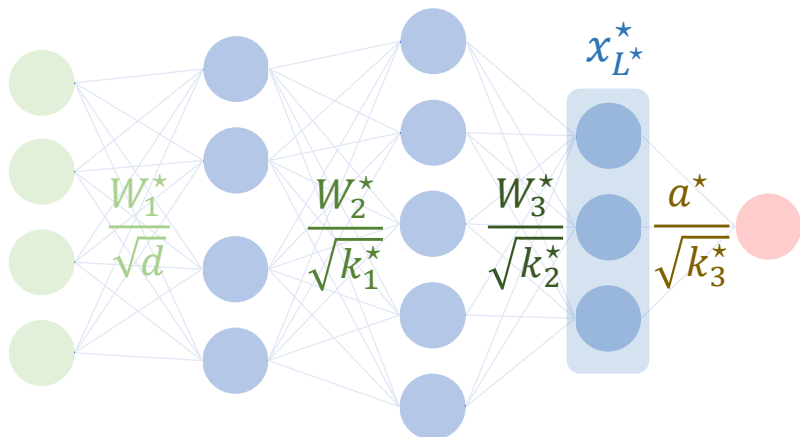
(ERMg)

Introduce the **Gaussian clones** u, v of x_L, x_{L^*}

$$u, v \sim \mathcal{N} \left(0, \begin{bmatrix} \langle x_L x_L^\top \rangle & \langle x_L x_{L^*}^\top \rangle \\ \langle x_{L^*} x_L^\top \rangle & \langle x_{L^*} x_{L^*}^\top \rangle \end{bmatrix} \right)$$

$$\mathcal{D} = \left\{ x^\mu, y^\mu = f^* \left(\frac{a_*^\top x_{L^*}^{\mu}}{\sqrt{k_{L^*}^*}} \right) \right\} \quad \hat{w} = \operatorname{argmin}_w \left(\sum_{\mu=1}^n g \left(y^\mu, \frac{w^\top x_L^\mu}{\sqrt{k_L}} \right) + r(w) \right)$$

$$\mathcal{D}^G = \left\{ u^\mu, y^\mu = f^* \left(\frac{a_*^\top v^\mu}{\sqrt{k_{L^*}^*}} \right) \right\} \quad \hat{w} = \operatorname{argmin}_w \left(\sum_{\mu=1}^n g \left(y^\mu, \frac{w^\top u^\mu}{\sqrt{k_L}} \right) + r(w) \right)$$

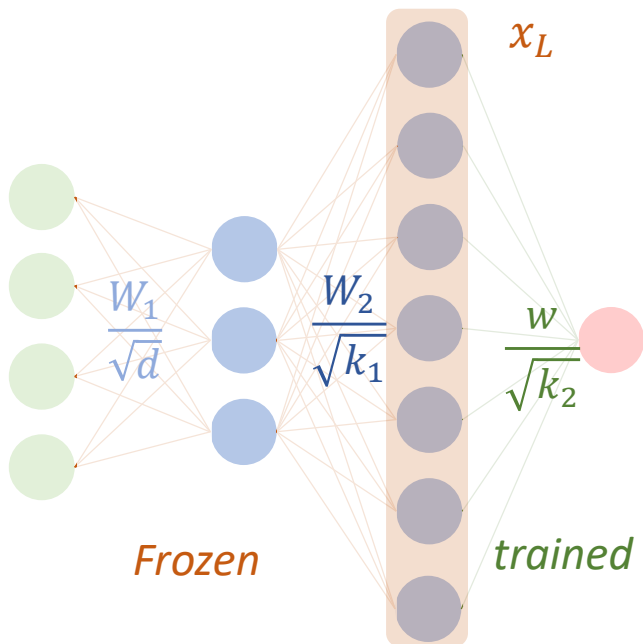


(ERM)

Introduce the **Gaussian clones** u, v of x_L, x_{L^*}

$$u, v \sim \mathcal{N} \left(0, \begin{bmatrix} \langle x_L x_L^\top \rangle & \langle x_L x_{L^*}^\top \rangle \\ \langle x_{L^*} x_L^\top \rangle & \langle x_{L^*} x_{L^*}^\top \rangle \end{bmatrix} \right)$$

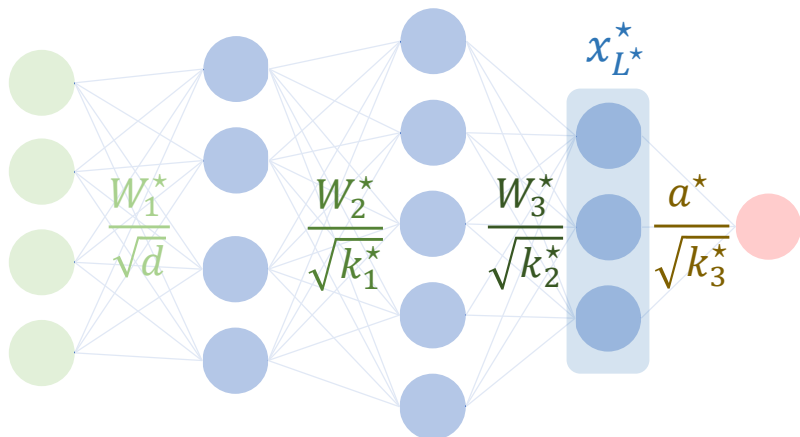
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(ERMg)

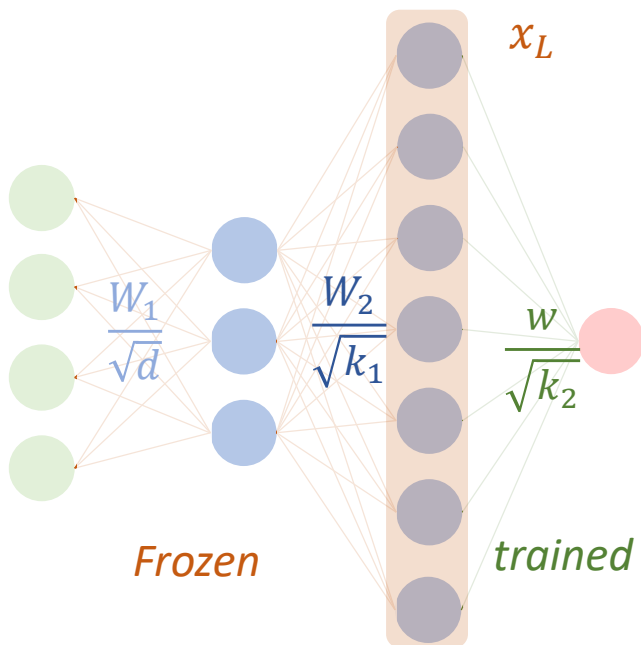
$$\mathcal{D}^G = \left\{ u^\mu, y^\mu = f^* \left(\frac{a_*^\top v^\mu}{\sqrt{k_{L^*}^*}} \right) \right\} \quad \hat{w} = \operatorname{argmin}_w \left(\sum_{\mu=1}^n g \left(y^\mu, \frac{w^\top u^\mu}{\sqrt{k_L}} \right) + r(w) \right)$$

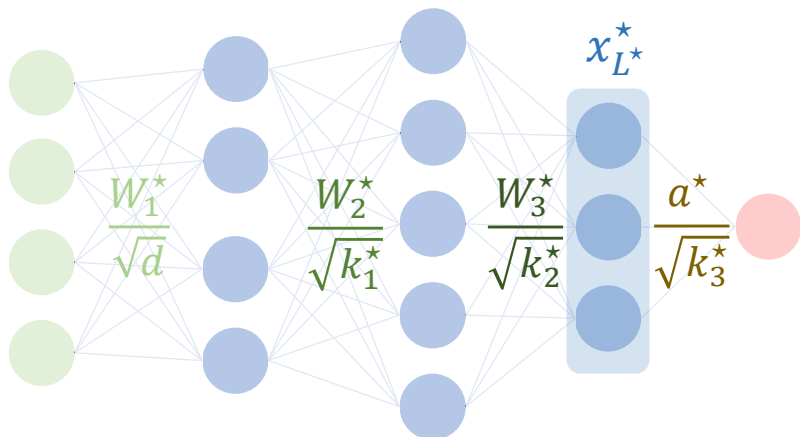
Conjecture: (part 1) (Gaussian universality) The learning problems (ERM) and (ERMg) lead to the same test error and training loss.



$$u, v \sim \mathcal{N}\left(0, \begin{bmatrix} \langle x_L x_L^\top \rangle & \langle x_L x_{L^*}^{*\top} \rangle \\ \langle x_{L^*}^* x_L^\top \rangle & \langle x_{L^*}^* x_{L^*}^{*\top} \rangle \end{bmatrix}\right)$$

Conjecture: (part 2) Furthermore, the covariances $\langle x_L x_L^\top \rangle$, $\langle x_{L^*}^* x_{L^*}^{*\top} \rangle$ and $\langle x_{L^*}^* x_L^\top \rangle$ can be computed simply with the noisy equivalent model.

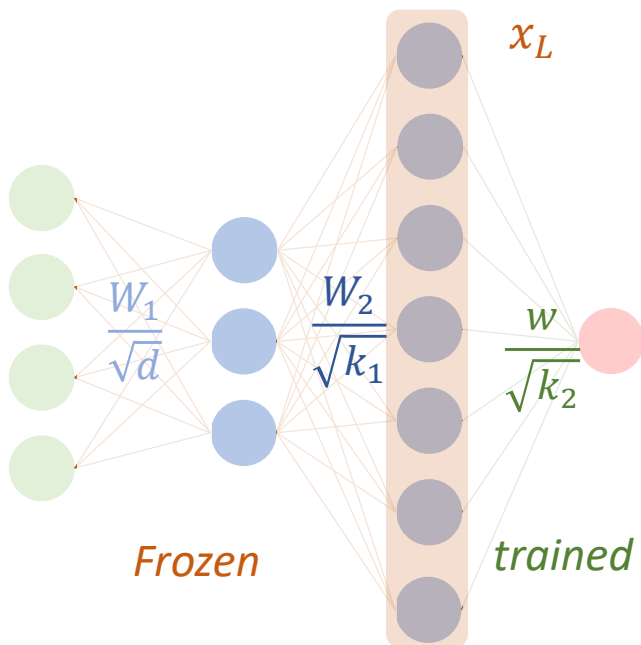




$$u, v \sim \mathcal{N}\left(0, \begin{bmatrix} \langle x_L x_L^\top \rangle & \langle x_L x_{L^*}^{*\top} \rangle \\ \langle x_{L^*}^* x_L^\top \rangle & \langle x_{L^*}^* x_{L^*}^{*\top} \rangle \end{bmatrix}\right)$$

Conjecture: (part 2) Furthermore, the covariances $\langle x_L x_L^\top \rangle$, $\langle x_{L^*}^* x_{L^*}^{*\top} \rangle$ and $\langle x_{L^*}^* x_L^\top \rangle$ can be computed simply with the noisy equivalent model.

Here for instance



$$\langle x_L x_L^\top \rangle = \kappa_1^{(1)^2} \kappa_1^{(2)^2} \frac{W_2 W_1 \Sigma W_1^\top W_2^\top}{d k_1} + \kappa_*^{(1)^2} \kappa_1^{(2)^2} \frac{W_2 W_2^\top}{k_1} + \kappa_*^{(2)^2} \mathbb{I}_{k_1}$$

$$\langle x_{L^*}^* x_{L^*}^{*\top} \rangle = \kappa_1^{*(1)^2} \kappa_1^{*(2)^2} \kappa_1^{*(3)^2} \frac{W_3^* W_2^* W_1^* \Sigma W_1^{*\top} W_2^{*\top} W_3^{*\top}}{d k_1^* k_2^*} + \kappa_*^{*(1)^2} \kappa_1^{*(2)^2} \kappa_1^{*(3)^2} \frac{W_3^* W_2^* W_2^{*\top} W_3^{*\top}}{k_1^* k_2^*} + \kappa_*^{*(2)^2} \kappa_1^{*(3)^2} \frac{W_3^* W_3^{*\top}}{k_2^*} + \kappa_*^{*(2)^2} \mathbb{I}_{k_2^*}$$

$$\langle x_{L^*}^* x_L^\top \rangle = \kappa_1^{(1)} \kappa_1^{(2)} \kappa_1^{*(1)} \kappa_1^{*(2)} \kappa_1^{*(3)} \frac{W_3^* W_2^* W_1^* \Sigma W_1^\top W_2^\top}{d \sqrt{k_1 k_1^* k_2^*}}$$

So one just needs to solve the proxy ERM

$$u, v \sim \mathcal{N}\left(0, \begin{bmatrix} \langle x_L x_L^\top \rangle & \langle x_L x_{L^*}^{\star\top} \rangle \\ \langle x_{L^*}^{\star} x_L^\top \rangle & \langle x_{L^*}^{\star} x_{L^*}^{\star\top} \rangle \end{bmatrix}\right)$$

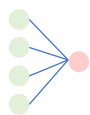
(ERMg)

$$\mathcal{D}^G = \left\{ u^\mu, y^\mu = f^*\left(\frac{a_\star^\top v^\mu}{\sqrt{k_{L^*}^\star}}\right) \right\}$$

$$\hat{w} = \underset{w}{\operatorname{argmin}} \left(\sum_{\mu=1}^n g\left(y^\mu, \frac{w^\top u^\mu}{\sqrt{k_L}}\right) + r(w) \right)$$

Theorem (informal) : The test error of the problem (ERMg) can be characterized in terms of three order parameters q, m, V given as the solution of a system of self-consistent equations.

$$\begin{cases} V = \mathbb{E}_{(\omega, \bar{\theta}) \sim \mu} \left[\frac{\omega}{\lambda + \hat{V}\omega} \right] \\ m = \frac{\hat{m}}{\sqrt{\gamma}} \mathbb{E}_{(\omega, \bar{\theta}) \sim \mu} \left[\frac{\bar{\theta}^2}{\lambda + \hat{V}\omega} \right] \\ q = \mathbb{E}_{(\omega, \bar{\theta}) \sim \mu} \left[\frac{\hat{m}^2 \bar{\theta}^2 \omega + \hat{q} \omega^2}{(\lambda + \hat{V}\omega)^2} \right] \end{cases}, \quad \begin{cases} \hat{V} = \frac{\alpha}{\hat{V}} (1 - \mathbb{E}_{s, h \sim \mathcal{N}(0,1)} [f'_g(V, m, q)]) \\ \hat{m} = \frac{1}{\sqrt{\rho\gamma}} \frac{\alpha}{\hat{V}} \mathbb{E}_{s, h \sim \mathcal{N}(0,1)} \left[s f_g(V, m, q) - \frac{m}{\sqrt{\rho}} f'_g(V, m, q) \right] \\ \hat{q} = \frac{\alpha}{\hat{V}^2} \mathbb{E}_{s, h \sim \mathcal{N}(0,1)} \left[\left(\frac{m}{\sqrt{\rho}} s + \sqrt{q - \frac{m^2}{\rho}} h - f_g(V, m, q) \right)^2 \right] \end{cases}$$



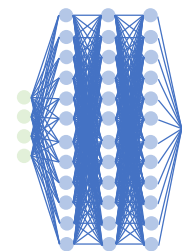
$$\epsilon_g = \rho \int z d\mu(z) + q - 2 \prod_{\ell=1}^L \kappa_1^{(\ell)} m + \epsilon_r$$

$$\begin{cases} \hat{V} = \frac{\alpha}{1+V} \\ \hat{q} = \alpha \frac{\epsilon_g}{(1+V)^2} \\ \hat{m} = \frac{\prod_{\ell=1}^L \kappa_1^{(\ell)} \alpha}{1+V} \end{cases} \begin{cases} V = \int \frac{z}{\lambda + \hat{V} z} d\mu(z) \\ q = \int \frac{\Delta_a \prod_{\ell=1}^L \Delta_\ell \hat{m}^2 z^3 + \hat{q} z^2}{(\lambda + \hat{V} z)^2} d\mu(z) \\ m = \Delta_a \prod_{\ell=1}^L \Delta_\ell \hat{m} \int \frac{z^2}{\lambda + \hat{V} z} d\mu(z) \end{cases}$$



$$\epsilon_g = \rho \int z d\mu(z) + q - 2 \prod_{\ell=1}^L \kappa_1^{(\ell)} m + \epsilon_r$$

$$\begin{cases} \hat{V} = \frac{\frac{\alpha}{\gamma}}{1+V} \\ \hat{q} = \frac{\alpha}{\gamma} \frac{\epsilon_g}{(1+V)^2} \\ \hat{m} = \sqrt{\Delta_a \prod_{\ell=1}^L \Delta_\ell \sqrt{\gamma} \frac{\prod_{\ell=1}^L \kappa_1^{(\ell)} \frac{\alpha}{\gamma}}{1+V}} \end{cases} \begin{cases} V = \frac{1}{\hat{V}} - \frac{\lambda}{\hat{V}^2 \kappa_1^2} g\left(-\frac{\lambda + \hat{V} \kappa_*^2}{\hat{V} \kappa_1^2}\right) \\ q = \frac{\hat{m}^2 + \hat{q}}{\hat{V}^2} - \frac{1}{\kappa_1^2 \hat{V}^2} \left(\frac{2\lambda(\hat{m}^2 + \hat{q})}{\hat{V}} + \hat{m}^2 \kappa_*^2 \right) g\left(-\frac{\lambda + \hat{V} \kappa_*^2}{\hat{V} \kappa_1^2}\right) \\ \quad + \frac{\lambda}{\kappa_1^4 \hat{V}^3} \left(\frac{\lambda(\hat{m}^2 + \hat{q})}{\hat{V}} + \hat{m}^2 \kappa_*^2 \right) g'\left(-\frac{\lambda + \hat{V} \kappa_*^2}{\hat{V} \kappa_1^2}\right) \\ m = \sqrt{\gamma} \frac{\hat{m}}{\hat{V}} \left[1 - \frac{1}{\kappa_1^2} \left(\frac{\lambda}{\hat{V}} + \kappa_*^2 \right) g\left(-\frac{\lambda + \hat{V} \kappa_*^2}{\hat{V} \kappa_1^2}\right) \right] \end{cases}$$



$$\epsilon_g = \rho \int z d\mu(z) + q - 2 \prod_{\ell=1}^L \kappa_1^{(\ell)} m + \epsilon_r$$

$$\begin{cases} \hat{V} = \frac{\alpha}{1+V} \\ \hat{q} = \alpha \frac{\epsilon_g}{(1+V)^2} \\ \hat{m} = \alpha \frac{\prod_{\ell=1}^L \kappa_1^{(\ell)}}{1+V} \end{cases} \begin{cases} V = \frac{\kappa_*^2}{\lambda} + \frac{\kappa_1^2}{\lambda + \hat{V} \kappa_1^2} \\ q = \frac{\Delta_a \prod_{\ell=1}^L \Delta_\ell \hat{m}^2 \kappa_1^4 + \hat{q} \kappa_1^4}{(\lambda + \hat{V} \kappa_1^2)^2} \\ m = \Delta_a \prod_{\ell=1}^L \Delta_\ell \hat{m} \frac{\kappa_1^2}{\lambda + \hat{V} \kappa_1^2} \end{cases}$$



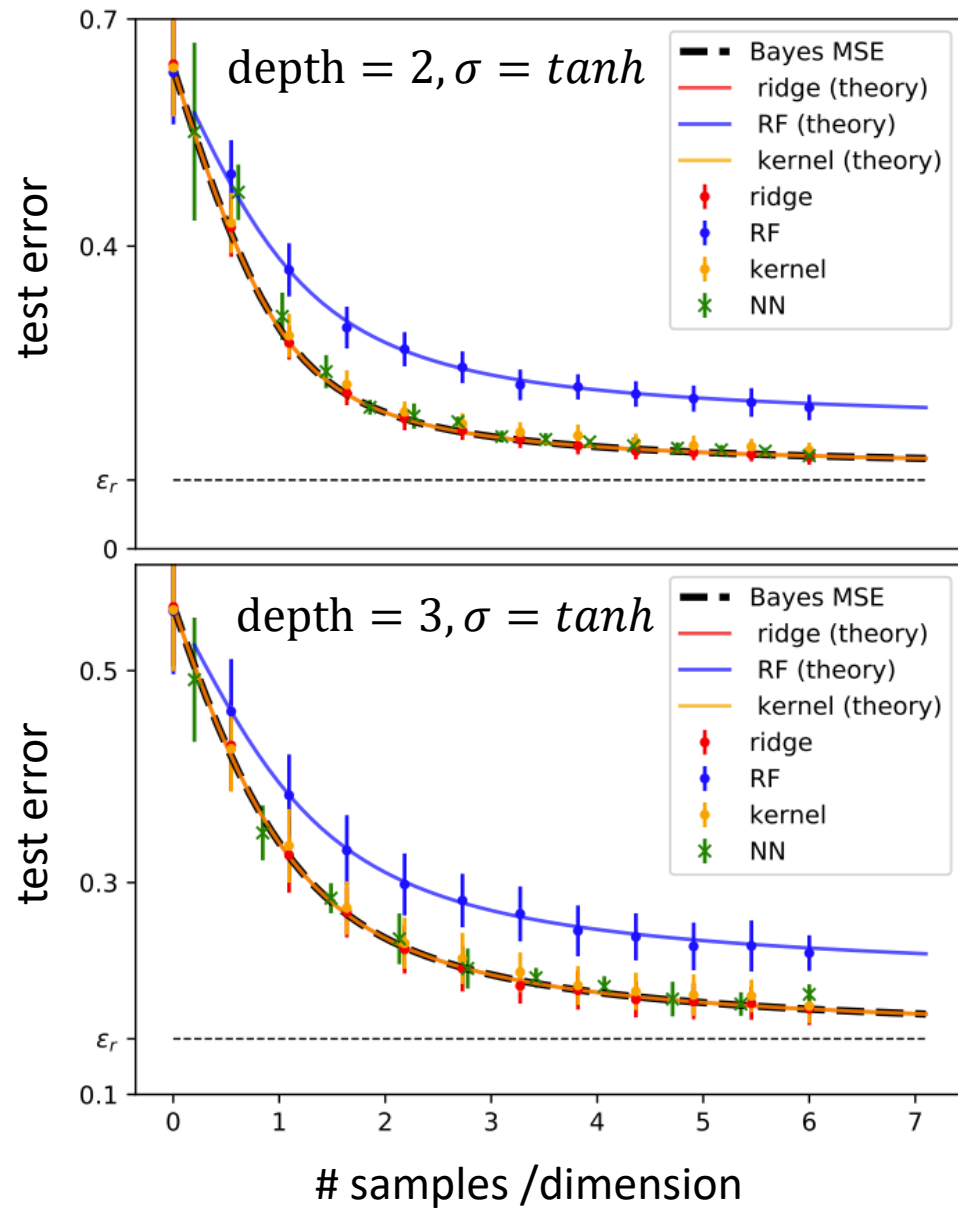
See Daniil's poster!

Summary:

- ✓ **Q1** We have sharp asymptotics for the Bayes optimal error of a deep, random network
= *lowest information theoretically achievable error*
- ✓ **Q2a** We have sharp asymptotics for test error of a large class of ERM algorithms on the same target.

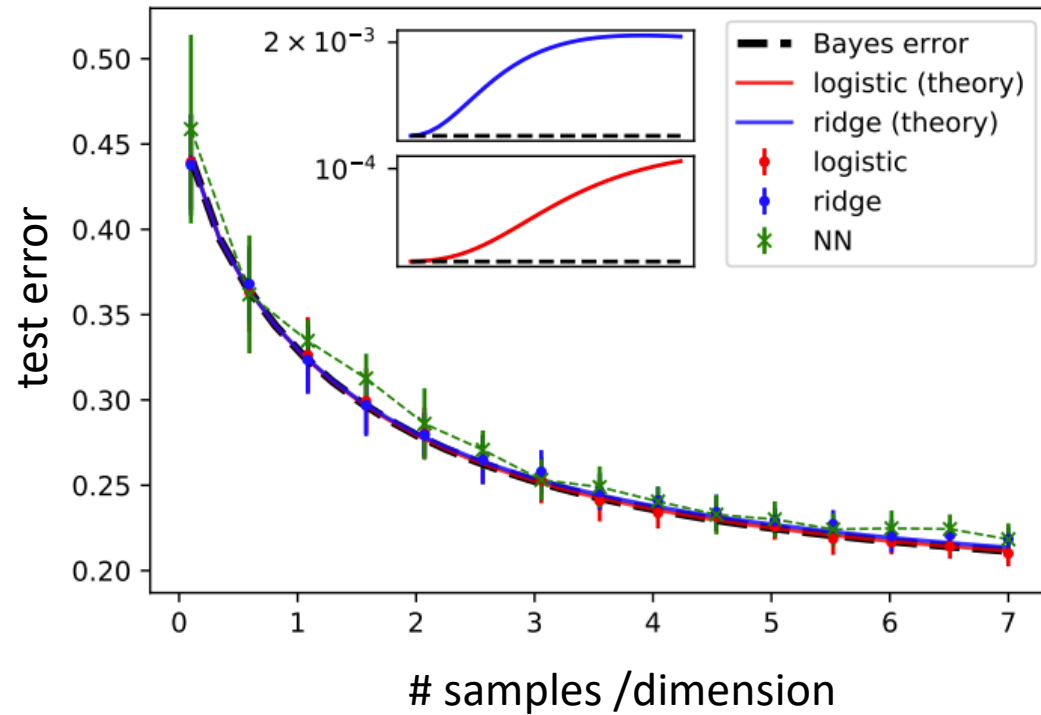
Q2b How do they compare?

Regression



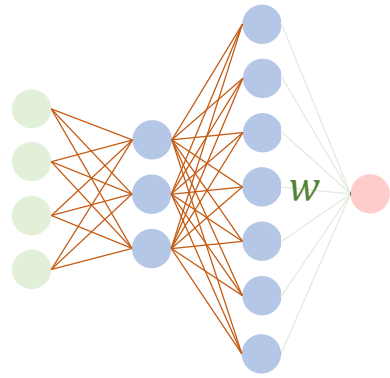
Optimally regularized ridge regression and kernel regression **are Bayes optimal**.

depth = 3, $\sigma = \tanh$



Optimally regularized logistic and ridge classification ***are close to Bayes optimal.***

(learner)



(GEP)

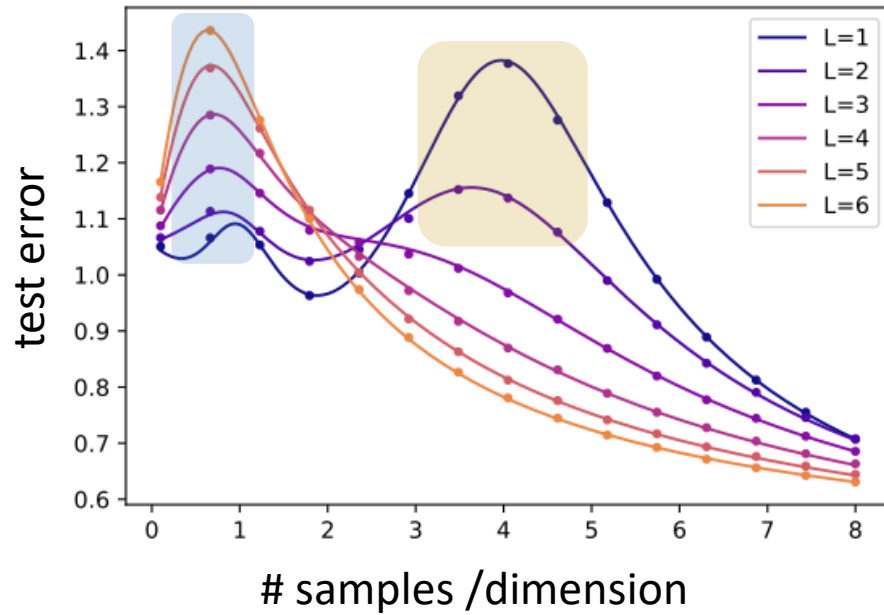
\approx

$$w^T \text{signal} Ax + \xi$$

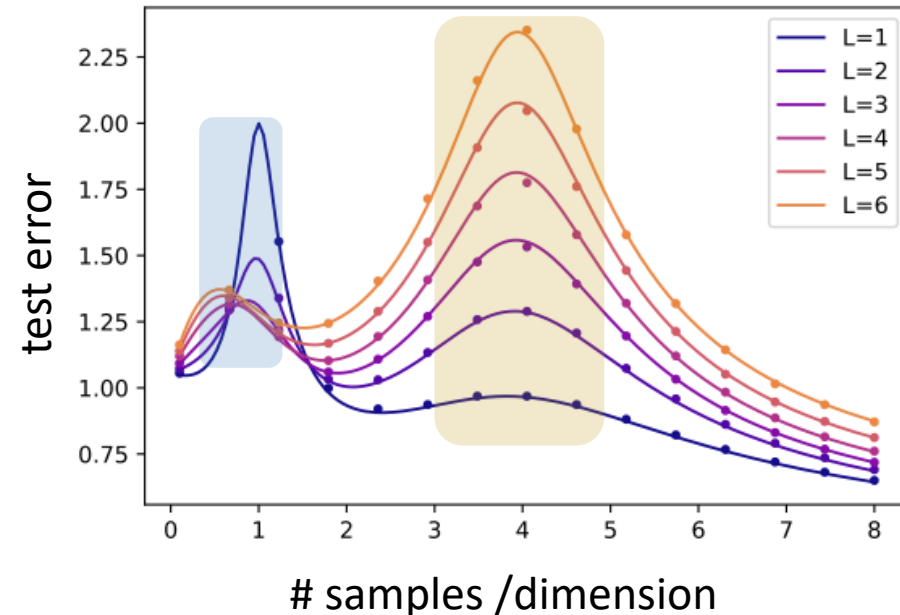
noise

When the **signal** is used to interpolate, the **noise** behaves as an depth-induced **implicit regularization**.

A second peak appears when the **noise** is used to interpolate the train set.



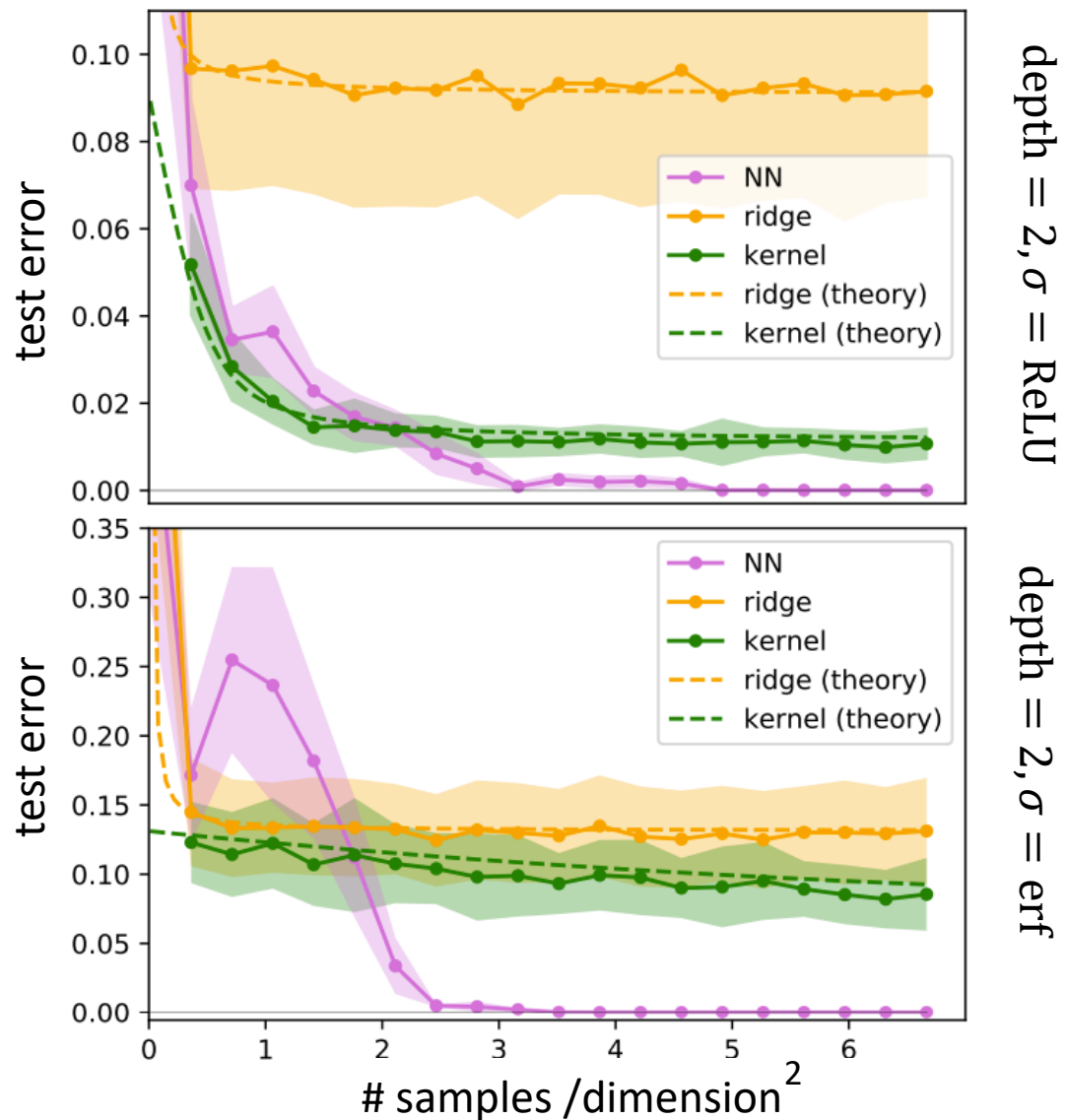
$$\sigma = \text{smooth sigmoid}$$



$$\sigma = \text{hard sigmoid}$$

Q2 Can ERM methods achieve the Bayes error?

A2 Yes, because in the $n \sim d$ regime ***only second-order statistics*** seem to be learnt, and in terms of those the target is equivalent to a single-layer network.



When $n \sim d^2$, *higher-order statistics are learnt*, the Gaussian equivalences break down.

Misiakiewicz, *Sharp asymptotics of kernel ridge regression beyond the linear regime*, 2022

Hu and Lu. *Sharp asymptotics of kernel ridge regression beyond the linear regime*, 2022

Bordelon, Canatar, Pehlevan. *Spectrum dependent learning curves in kernel regression and wide neural networks*, 2020

Takeaways:

- In terms of *second order statistics* wrt a Gaussian input, a deep non-linear network is equivalent to a noisy linear network.
- Hence, In the $n \sim d$ regime, they are *characterized by the same Bayes / ERM errors*.
- Thus, single-layer ERM learners are Bayes optimal.

Challenge /Future work:

There is a need for a theory of finite-width architectures in *super linear regimes*.

Takeaways:

- In terms of *second order statistics* wrt a Gaussian input, a deep non-linear network is equivalent to a noisy linear network.
- Hence, In the $n \sim d$ regime, they are *characterized by the same Bayes / ERM errors*.
- Thus, single-layer ERM learners are Bayes optimal.

Challenge /Future work:

There is a need for a theory of finite-width architectures in *super linear regimes*.

Thank you for your attention !